

# Temperature Dependent Hole Mobility in MBE grown $\text{GaAs}_{1-x}\text{Bi}_x$

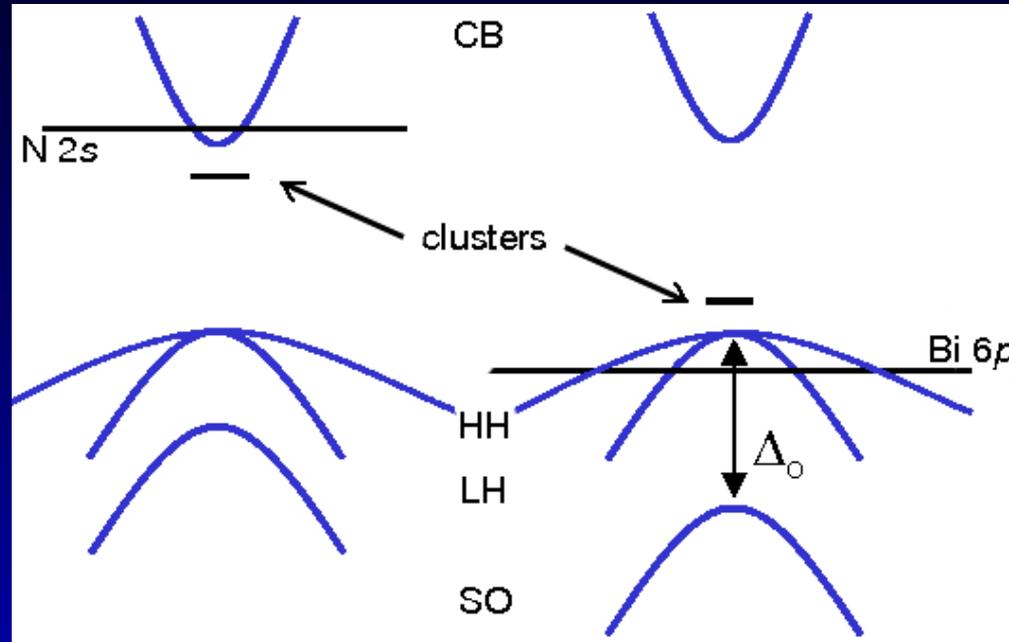
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- Sample growth and fabrication
- Growth conditions and hole mobility
- $\text{GaAs}_{1-x}\text{Bi}_x$  hole mobility
- Temperature dependence

# N and Bi in GaAs



- Nitrogen perturbs the conduction band and reduces electron mobility
- Expect Bismuth to perturb valence band and effect hole mobility

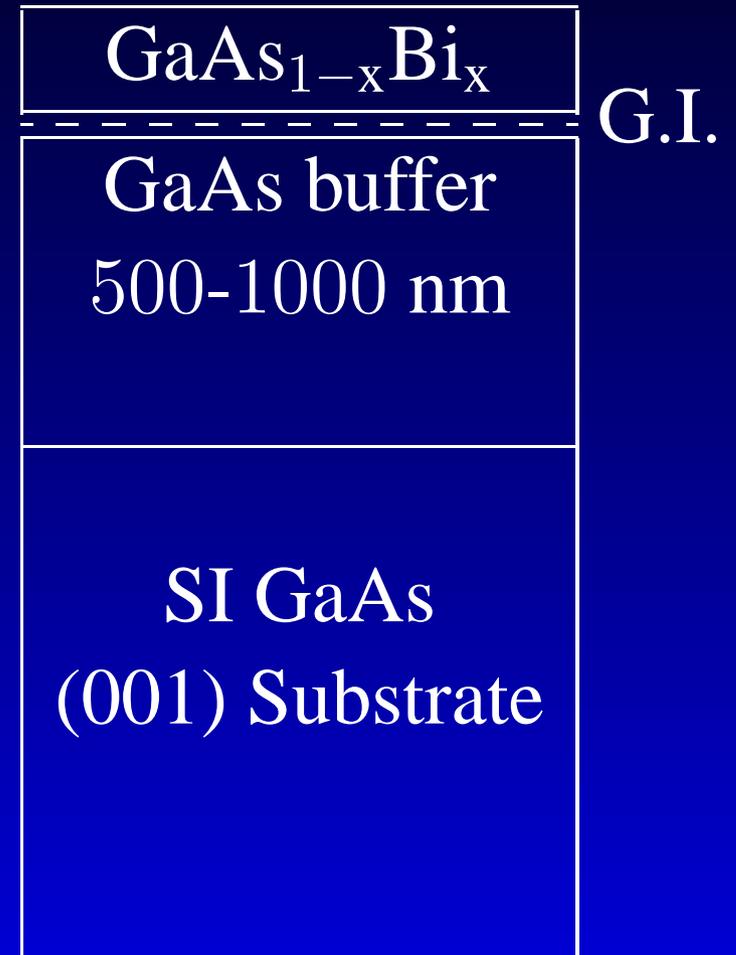
# MBE Growth of $\text{GaAs}_{1-x}\text{Bi}_x$

## GaAs buffer

- $T_{\text{grow}} \simeq 580^\circ\text{C}$
- As:Ga ratio  $\simeq 8$
- Growth rate  $\simeq 1 \mu\text{m/hr}$
- Ga BEP  $\simeq 2 \times 10^{-7}$  Torr

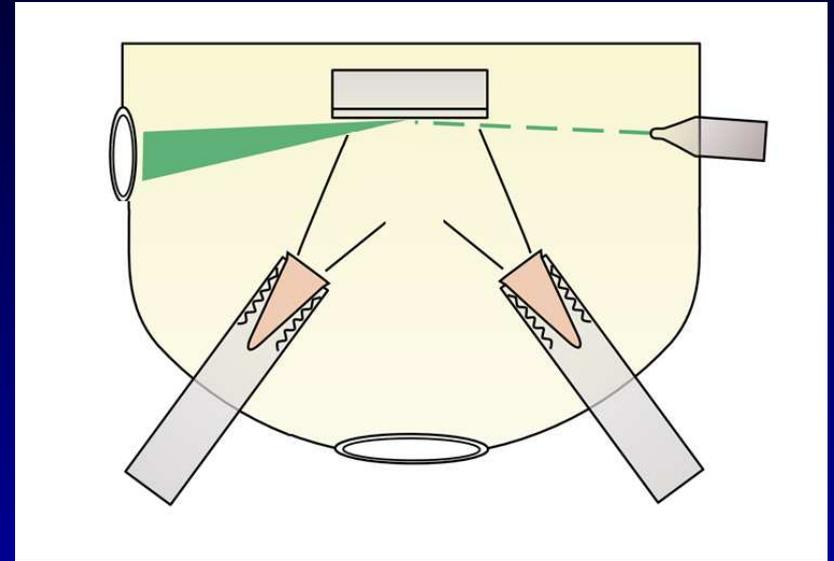
## GaAsBi

- $T_{\text{grow}} \simeq 350^\circ\text{C}$
- Growth rate  $\simeq 0.1 \mu\text{m/hr}$
- As:Ga ratio  $\simeq 1 - 2.0$
- Bi BEP  $\simeq 5 \times 10^{-10}$  Torr



# MBE Growth

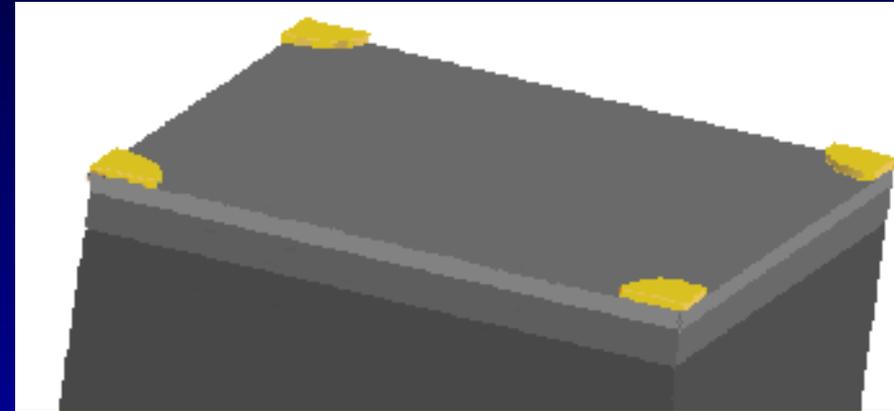
- Effusion cells for Ga, Bi
- Valved two-zone cracker for  $\text{As}_2$
- Carbon dopant from  $\text{CBr}_4$  flow controlled gas source
- *In-situ*: Band gap thermometry, RHEED, Light scattering



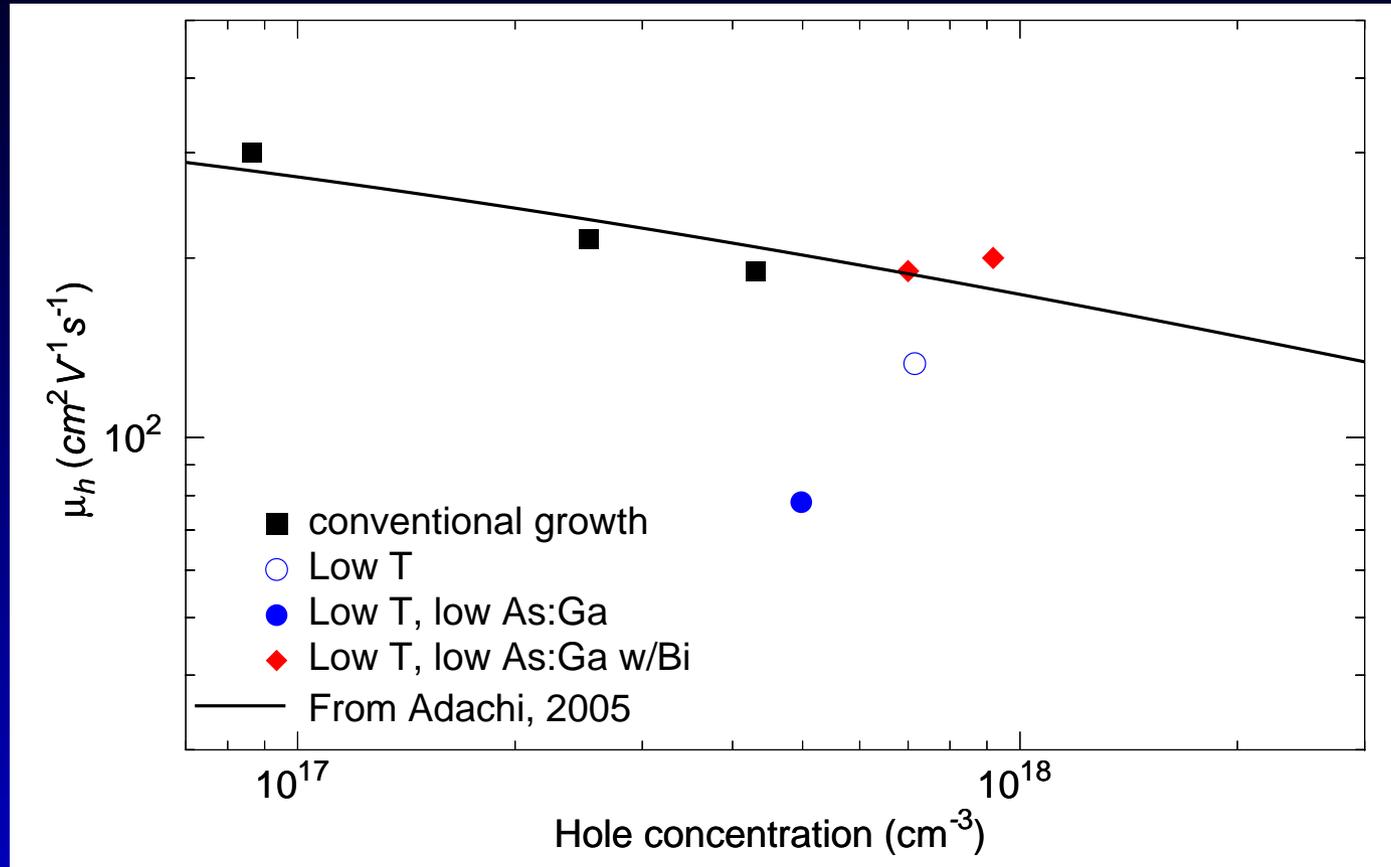
VG-80H MBE  
Chamber

# Hall Measurements

- Thicknesses 250 – 1000 nm
- Doping:  $8 \times 10^{16} - 2 \times 10^{18} \text{ cm}^{-3}$
- Depletion widths = 70-20 nm
- $7 \times 7$  mm squares
- Ti/Pt/Au Ohmic contacts
- Van der Pauw method
- $B = 0.265$  T
- Temperatures of 25-300 K

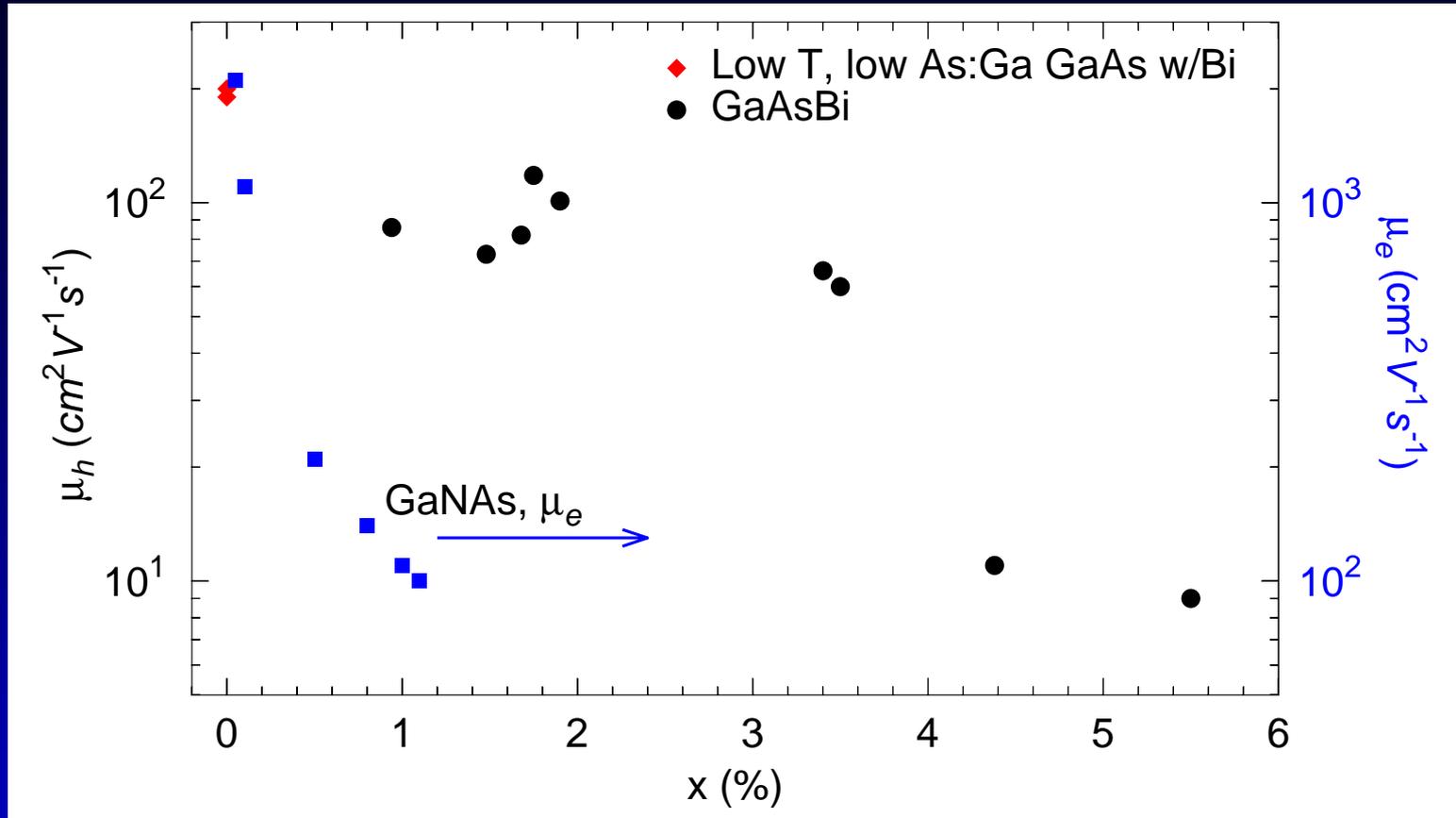


# Hole Mobility of p-GaAs



- Low temperature growth of GaAs with Bi surfactant shows no reduction in hole mobility

# Hole Mobility of p-GaAs<sub>1-x</sub>Bi<sub>x</sub>



- Hole mobility decreases with increasing [Bi]
- Effect weaker than N incorporation on electron mobility

# Mobility Temp. Dep.

- Contributions from phonons, ionized impurities and Bi incorporation

$$\frac{1}{\mu} = \frac{1}{C_{\text{ph}} T^{1.5}} + \frac{T^{1.5}}{C_{\text{I}}} + \frac{1}{C_{\text{Bi}}}$$

- Kinetic Theory;  $\frac{1}{N_{\text{Bi}} \sigma} = \frac{v m^* C_{\text{Bi}}}{q}$

- Fahy *et al.* <sup>1</sup>;  $\sigma = \frac{1}{16\pi} \left(\frac{m^*}{\hbar^2}\right)^2 \left(\frac{dE_g}{dx}\right)^2 a^6$

a is GaAs lattice parameter,  $\frac{dE_g}{dx} = 8.8 \text{ eV}$

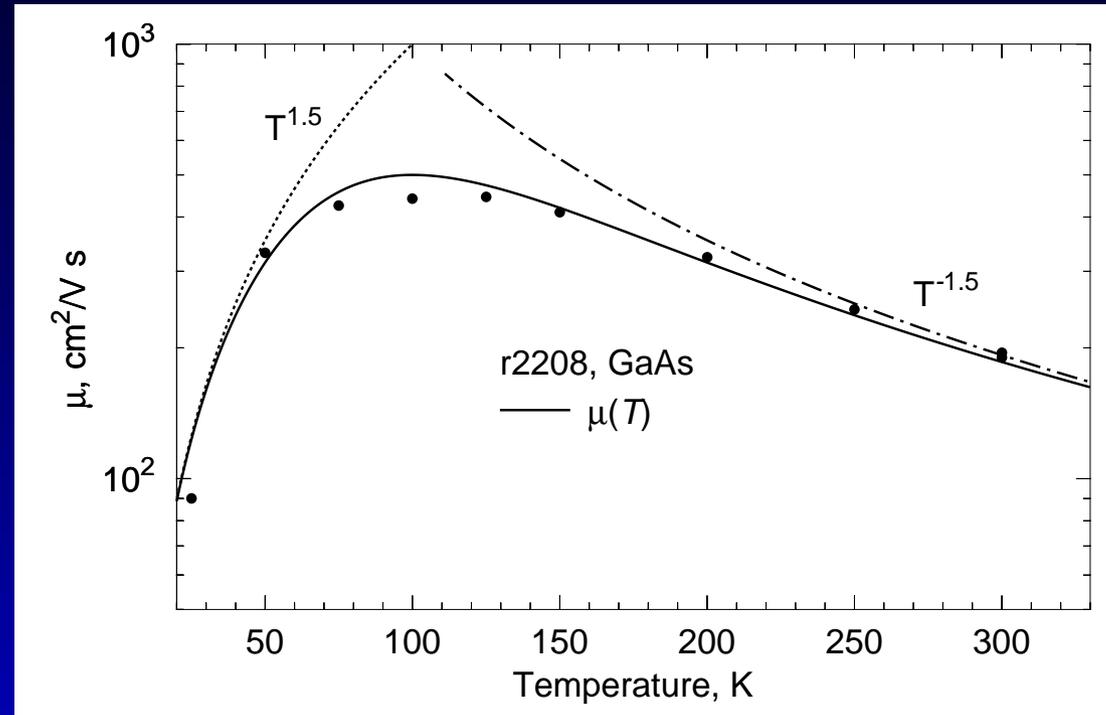
$$\rightarrow \sigma = 2.0 \text{ nm}^2$$

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<sup>1</sup> S. Fahy, A. Lindsay and E.P. O'Reilly, IEE Proc. Optoelectron. **151**, 352 (2004)

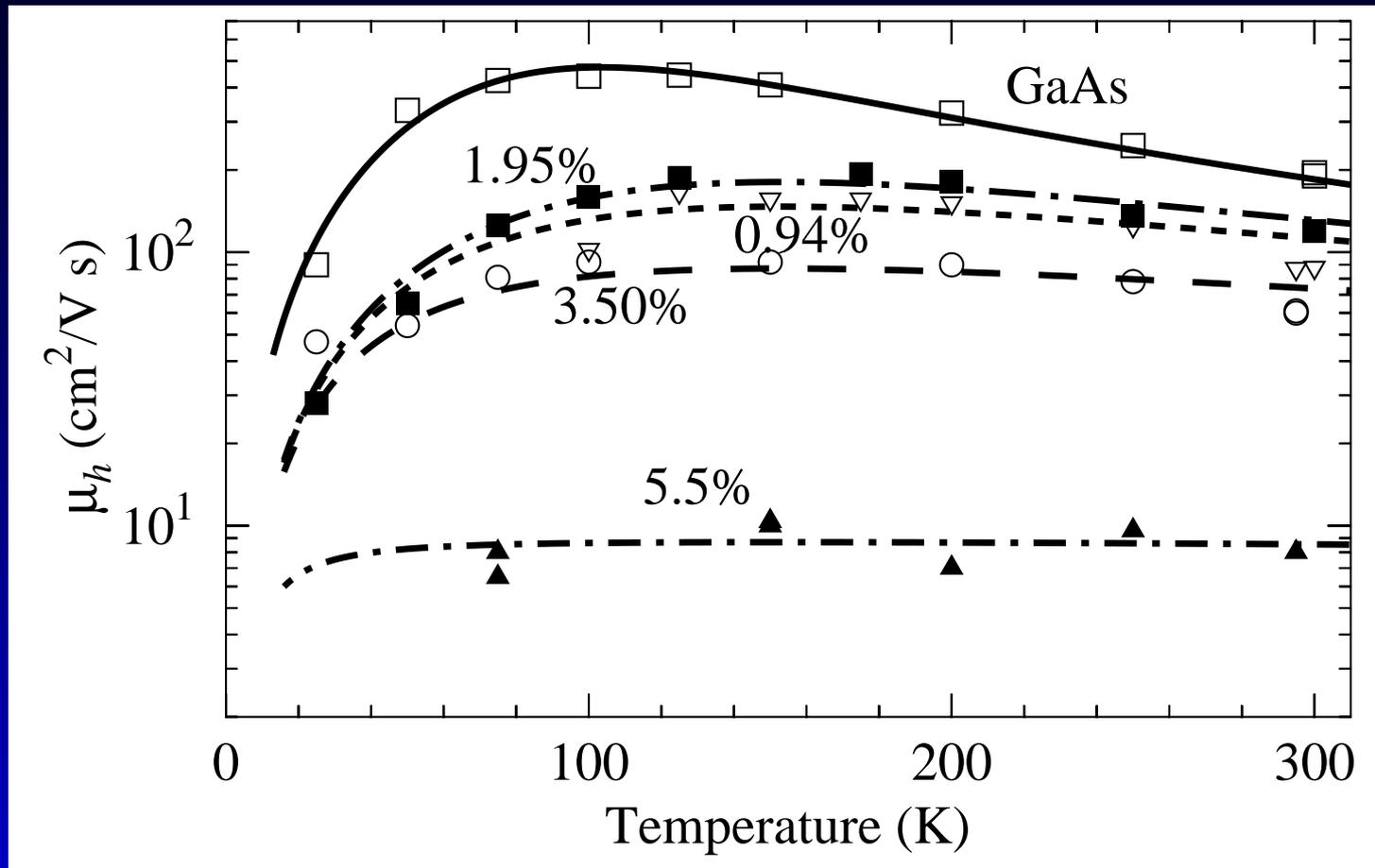
# Mobility Temp. Dep. in GaAs

$T_{grow} = 350^{\circ}\text{C}$  ; As:Ga  $\simeq 2$  ; w/ Bi surfactant



- Bismide-like growth conditions, GaAs<sub>1-x</sub>Bi<sub>x</sub>  
x = 0
- Will use  $C_{ph}$  from this sample for GaAs<sub>1-x</sub>Bi<sub>x</sub> samples

# Mobility Temp. Dep. in $\text{GaAs}_{1-x}\text{Bi}_x$



- Increasing effect from  $C_{Bi}$  with increasing [Bi]

# Mobility Temp. Dep. in $\text{GaAs}_{1-x}\text{Bi}_x$

[Bi] (%)	0%	0.94%	1.95%	3.5%	5.5%
$\mu(300K) \left( \frac{\text{cm}^2}{\text{V}\cdot\text{s}} \right)$	200	88	100	60	8
$C_{ph}$	$1.0 \times 10^6$	$1.0 \times 10^6$	$1.0 \times 10^6$	$1.0 \times 10^6$	-
$C_I$	0.9	0.28	0.28	0.28	0.28
$C_{Bi}$	-	330	570	130	9

isolated Bi,  $\sigma_{\text{Bi}} = 0.2 \text{ nm}^2$

$2.0 \text{ nm}^2$

# Conclusions

- Low temperature growth of GaAs with Bi surfactant shows no reduction in hole mobility
- Decreasing hole mobility for increasing [Bi] in  $\text{GaAs}_{1-x}\text{Bi}_x$  up to  $x = 5.5\%$
- Weaker effect than decreasing electron mobility in  $\text{GaN}_x\text{As}_{1-x}$
- Effect of Bi modeled with temperature independent term
- Estimated  $\sigma = 0.2\text{-}2.0 \text{ nm}^2$

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*Thank you*